



<b>Search Notes</b>  	Application/Control No.  09116124	Applicant(s)/Patent Under Reexamination  NISHINA ET AL.
	Examiner Tran, Hai	Art Unit 2623


Notes	Date	Examiner
EAST TEXT SEARCH ATTACHED; Son Huynh (725); Rueben Brown (725)	10/16/2006	HVT
William Bashore (715)	9/21/2006	HVT
U.S. Patent and Trademark Office		Part of Paper No.: 20061016

<b><i>Interference Searched</i></b>  	Application/Control No.  09116124	Applicant(s)/Patent Under Reexamination  NISHINA ET AL.
	Examiner Tran, Hai	Art Unit 2623

Class	SubClass	Date	Examiner
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Interference searched attached	10/16/2006	HVT
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<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>09116124</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>NISHINA ET AL.</p>
	<p>Examiner</p> <p>Tran, Hai</p>	<p>Art Unit</p> <p>2623</p>

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UPDATE SEARCH	10/16/2006	HVT
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